

## **SEM - resolution**

**Topography imaging (secondary electrons):**

**Resolution = electron beam diameter = d**

$$d = \sqrt{\frac{i}{E}} \frac{a}{r}$$

**i = beam current (probe current, spot size):  $10^{-12} - 10^{-6}$  A**

**E= acceleration voltage : 5-20kV**

**a= working distance (distance between objective lens and specimen) ; 5-50mm**

## **SEM – depth of field**

**Depth of field = maximum difference in height where an image of a specimen is in focus = D**

$$D = \left( \frac{\delta}{M} - d \right) \frac{a}{r}$$

**$\delta$  = resolution of the eye = 0.1mm**

**a = working distance : 5-50mm**

**r = aperture radius (typical 3-4 values)**